Attorney's Docket No.: 12732-038001 / US4917/4945

1 2 2003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Spplicant: Hideomi Suzawa et al.

Art Unit : 2812

Serial No.: 09/852,672

Examiner: Viktor Simkovic

Filed

: May 11, 2001

Title

: SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Applicants submit the references listed on the attached form PTO-1449.

Applicants note that U.S. Application No. 09/852,282, which is the subject of U.S. Patent Application Publication US 2002/0006705 (Desig. ID AA), is directed to subject matter related to that of the present application.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: November 12, 2003

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Substitute Form PTO-1449 (Modified)

U.S. Department of Commerce Patery and Trademark Office

Attorney's Docket No. 12732-038001

Application No. 09/852,672

Pater and Trade by Applicant (Use several sheets if necessary)

<u>1 2 2003</u>

Applicant Hideomi Suzawa et al.

Group Art Unit

(37 CFR §1.98(b))

Filing Date May 11, 2001 2812

U.S. Patent Documents											
Examiner Des Initial ID		Document Number	Publication Date	Patentee	Class	Sub- class	Filing Date If Appropriate				
	AA	US 2002/0006705 A1	01/17/2002	Suzawa et al.			05/10/2001				
	AB	4,963,504	10/16/1990	Huang			11/24/1989				
	AC	5,182,619	01/26/1993	Pfiester			09/03/1991				
	AD	5,185,058	02/09/1993	Cathey, Jr.			01/29/1991				
	AE	5,272,100	12/21/1993	Satoh et al.			08/07/1991				
	AF	5,302,240	04/12/1994	Hori et al.			02/19/1993				
	AG	5,378,309	01/03/1995	Rabinzohn			08/05/1992				
	AH	5,543,340	08/06/1996	Lee			12/27/1994				
	AI	5,581,092	12/03/1996	Takemura			09/06/1994				
	AJ	5,583,067	12/10/1996	Sanchez			02/16/1996				
	AK	5,633,738	05/27/1997	Wakui et al.			05/25/1995				
	AL	5,643,826	07/01/1997	Ohtani et al.			10/25/1994				
	AM	5,767,530	06/16/1998	На			09/26/1997				
	AN	5,767,930	06/16/1998	Kobayashi et al.			05/20/1997				
	AO	5,825,437	10/20/1998	Seo et al.			02/13/1996				
	AP	5,828,103	10/27/1998	Hsu			12/26/1995				
	AQ	5,841,170	11/24/1998	Adan et al.			01/14/1997				
	AR	5,917,199	06/29/1999	Byun et al.			05/15/1998				
	AS	5,923,961	07/13/1999	Shibuya et al.			11/12/1997				
	AT	5,923,962	07/13/1999	Ohtani et al.			04/28/1995				
	AU	5,923,999	07/13/1999	Balasubramanyam et al.			10/29/1996				
	AV	6,259,138	07/10/2001	Ohtani et al.			12/16/1999				
	AW	6,369,410	04/09/2002	Yamazaki et al.			12/15/1998				

Foreign Patent Documents or Published Foreign Patent Applications													
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No						
	AX	10-233511	09/02/1998	JAPAN			Full						

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.